“Scanning probe microscopy for physical and chemical property characterizations at the nanoscale”

The seminar will review the scanning probe based measurement technologies with focus on recent technology evolutions in quantitative physical and chemical property characterizations. We will briefly explain principles of each probe based characterization method, including mechanical, electric/magnetic, as well as the spectroscopy based chemical analyses. Finally we will show applications using the scanning probe technology in the fields of biology, materials science and semiconductor industries.

Please contact marla@chem.ucla.edu for additional information.